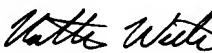
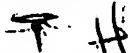


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/716,912		ATMUR ET AL.	
				Examiner		Art Unit	
				Nathan Wiehe		3745	

ISSUE CLASSIFICATION				
ORIGINAL		CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	
416	30	416	155	
INTERNATIONAL CLASSIFICATION		440	50	
B	6	3	H	3/02
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				/
				/
 1/4/06 (Assistant Examiner) (Date)		 1/6/06 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)		Total Claims Allowed: 15
 1-23 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s) 1		O.G. Print Fig. 9

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input checked="" type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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